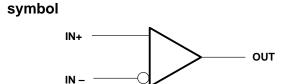
- Operates From a 5-V Supply
- Self-Biasing Inputs
- Hysteresis . . . 10 mV Typ
- Response Time . . . 6 ns Typ
- Maximum Operating Frequency 50 MHz Typ

description

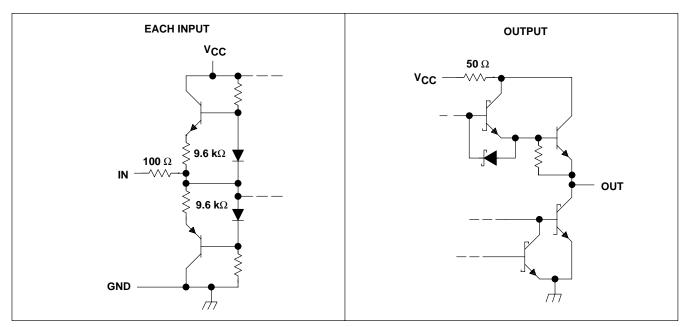
The TL714C is a high-speed differential comparator fabricated with bipolar Schottky process technology. The circuit has differential inputs and a TTL-compatible logic output with symmetrical switching characteristics.



The device operates from a single 5-V supply and is useful as a disk-memory read-chain data comparator.

The TL714C is characterized for operation from 0°C to 70°C.

schematic of inputs and outputs



All resistor values shown are nominal.

TL714C HIGH-SPEED DIFFERENTIAL COMPARATOR

SLCS015 - DECEMBER 1988 - REVISED JUNE 1989

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Storage temperature range – 65°C to 150°C

- NOTES: 1. All voltage values, except differential voltage, are with respect to the network ground.
 - 2. Differential voltage values are at IN+ with respect to IN -.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR	DERATE ABOVE T _A	T _A = 75°C POWER RATING
D	500 mW	5.8 mW/°C	64°C	464 mW
Р	500 mW	N/A	N/A	500 mW

recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, V _{CC}	4.75	5.25	V
Common-mode input voltage, V _{IC}	1.4 to V _{CC} – 1.4		V
High-level output current, IOH		- 1	mA
Low-level output current, IOL		16	mA
Operating free-air temperature, T _A	0	70	°C

electrical characteristics over free-air operating temperature range, V_{CC} = 5 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
٧T	Threshold voltage (V _{T+} – V _{T-})	V _{IC} = 1.4 V to 3.6 V	-75§		75	mV
V _{hys}	Hysteresis (V _{T+} – V _T _)		2	10	30	mV
Vон	High-level output voltage	$V_{ID} = 100 \text{ mV}, \qquad I_{OH} = -1 \text{ mA}$	2.7	3.4		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV}, I_{OL} = 16 \text{ mA}$		0.4	0.5	V
los	Short-circuit output current		- 30		- 110	mA
rį	Differential input resistance		2.9			kΩ
ICC	Supply current	$V_{ID} = -100 \text{ mV}, I_{O} = 0$		7	12	mA

[‡] All typical values are at T_A = 25°C.



[†] Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the recommended operating conditions section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] The algebraic convention, where the more negative limit is designated as minimum, is used in this data sheet for input threshold voltage levels only.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
fmax	Maximum operating frequency	$V_{ID} = \pm 250 \text{ mV},$ $C_L = 25 \text{ pF},$	$t_f = t_f = 4 \text{ ns},$ Input duty cycle = 50%		50		MHz
tPLH	Propagation delay time, low-to-high-level output	$V_{ID} = \pm 100 \text{ mV},$	C _L = 25 pF,		6	12	ns
tPHL	Propagation delay time, high-to-low-level output	See Figures 1 and 2			6	12	ns
t _r	Rise time	$V_{ID} = \pm 100 \text{ mV},$	C _L = 25 pF,		4	8	ns
tf	Fall time	See Figure 3			4	8	ns

[†] All typical values are at $T_A = 25$ °C.

PARAMETER MEASUREMENT INFORMATION

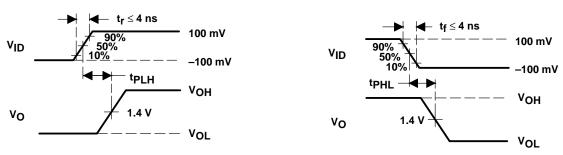


Figure 1. Propagation Delay Time, Low to High (t_{PLH})

Figure 2. Propagation Delay Time, High to Low (t_{PHL})

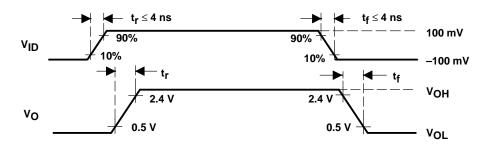


Figure 3. Rise and Fall Times (t_r, t_f)

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